

# The Impact of WBG Devices on Next Generation Integrated Power Electronics



**Isik C. Kizilyalli**

Associate Director of Technology and Program Director  
Advanced Research Projects Agency – Energy (ARPA-E)  
U.S. Department of Energy  
[isik.kizilyalli@hq.doe.gov](mailto:isik.kizilyalli@hq.doe.gov)



**Eric P. Carlson**

Lead Scientist  
Booz Allen Hamilton  
Support Contractor to ARPA-E  
[eric.carlson@hq.doe.gov](mailto:eric.carlson@hq.doe.gov)

The 7<sup>th</sup> International Workshop on  
Power-Supply-on-Chip (PwrSoC)  
October 25, 2021

# ARPA-E Mission

**Goal 1:** To enhance the economic and energy security of the United States through the development of energy technologies that—

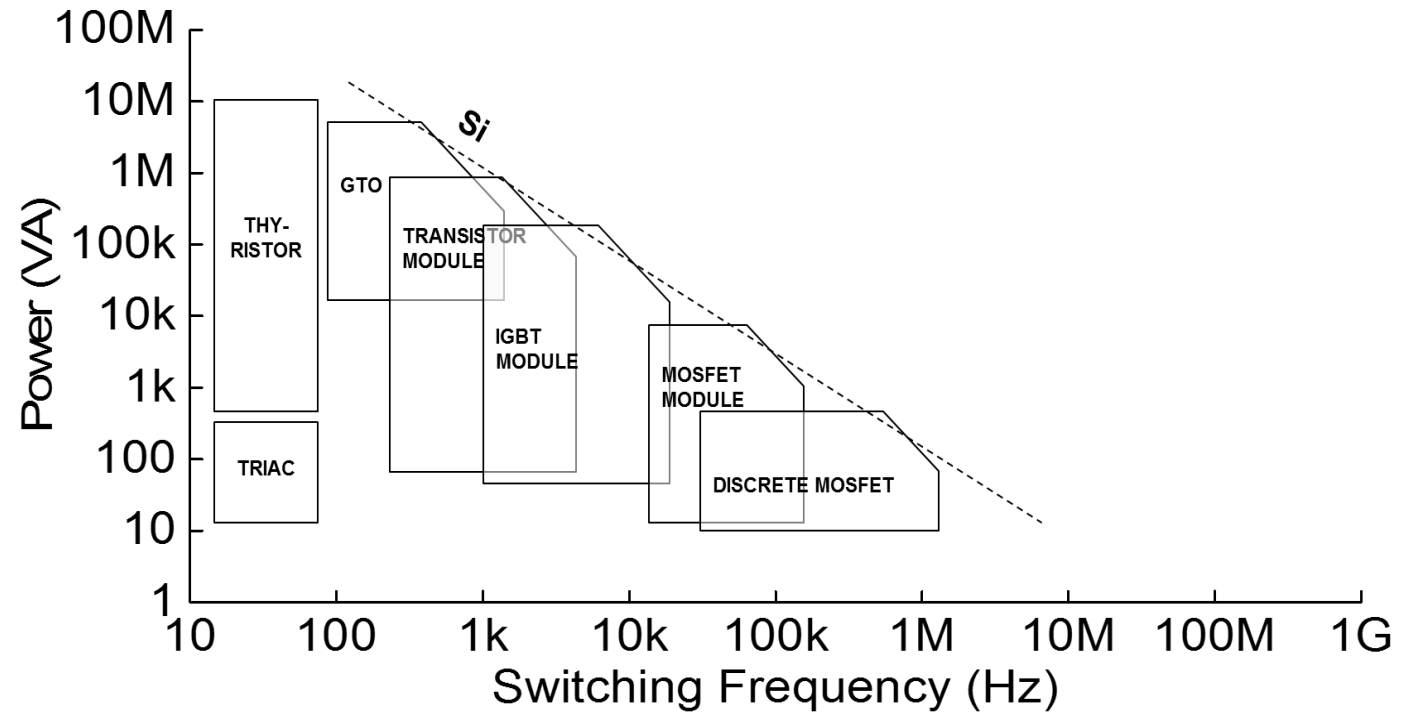


**Goal 2:** To ensure that the United States maintains a technological lead in developing and deploying advanced energy technologies.

# What are the Benefits of Integration?

**Moving from discrete devices to modules to ICs allows for:**

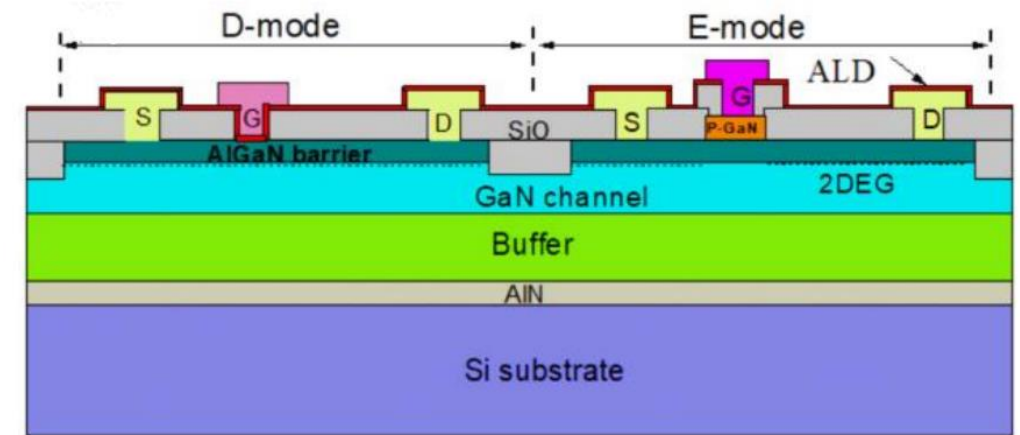
- **Smaller size**
- **Increased reliability**
- **Reduced parasitics**
- **Reduced cost**



**Wide bandgap semiconductors allow for faster switching but parasitic inductance becomes a performance limiter at fast switching rate**

# What are the Challenges in Integration?

- ▶ High voltage device isolation needed
- ▶ High voltage/power device performance is critical
- ▶ Need Resistors and Capacitor passives (low-voltage)
- ▶ Multiple metal layers needed for signal routing and ground/power planes
- ▶ Complementary (p-type, n-type) transistor process is challenging. Nice to have but perhaps not essential enough to trade-off on power device performance.

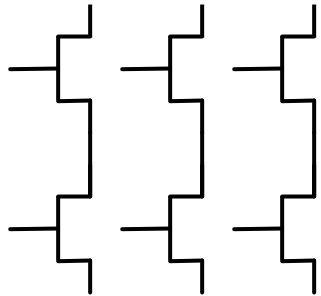


Micromachines 2021, 12, 617. <https://doi.org/10.3390/mi12060617>

# Power IC : Types of Integration

## Power Device Only

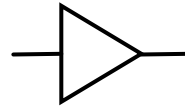
Several high-voltage power devices of same type on same chip



- Diode bridge
- H-bridge transistors
- Half-bridge transistors

## Driver Circuit Only

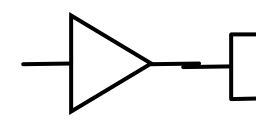
Low voltage (GaN or SiC) driver circuit to be used to drive a power device



- Advantage of thermal compatibility with power device
- Driver ideal for use in modules

## Driver + Power Device

Low voltage drivers on same chip with GaN or SiC power device



- Minimum parasitic R,L,C
- “Saves” cost of module integration
- “Wastes” expensive high-voltage chip area for low-voltage devices

# CIRCUITS

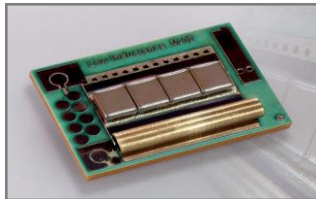
Creating Innovative and Reliable Circuits Using Inventive Topologies and Semiconductors



Kickoff Year	2017
Projects	21
Investment	\$31.9M
Duration	18-36 months

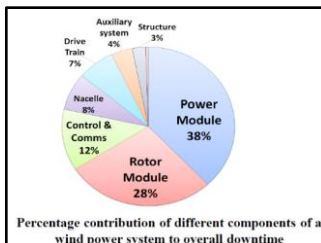
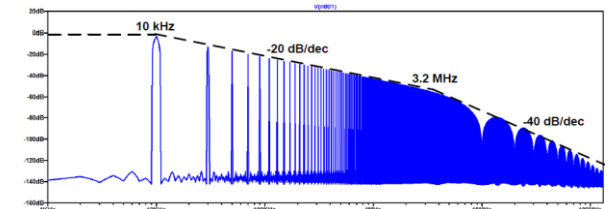
**Goal:** Use advanced circuit topologies and fundamentally higher performing WBG semiconductor materials to realize efficiency gains both directly and indirectly in electric power conversion

1. Innovate on circuit topology and controls to increase power density



2. Innovate on Packaging and modules to reduce parasitics

3. Manage conductive and radiative noise (EMI) of fast switching devices



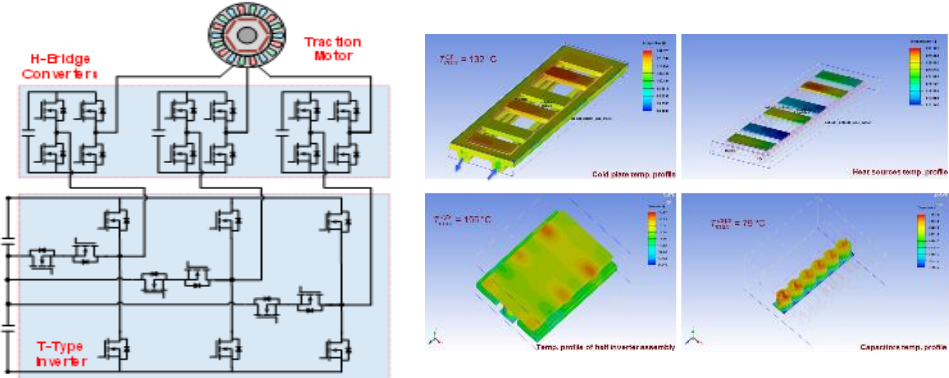
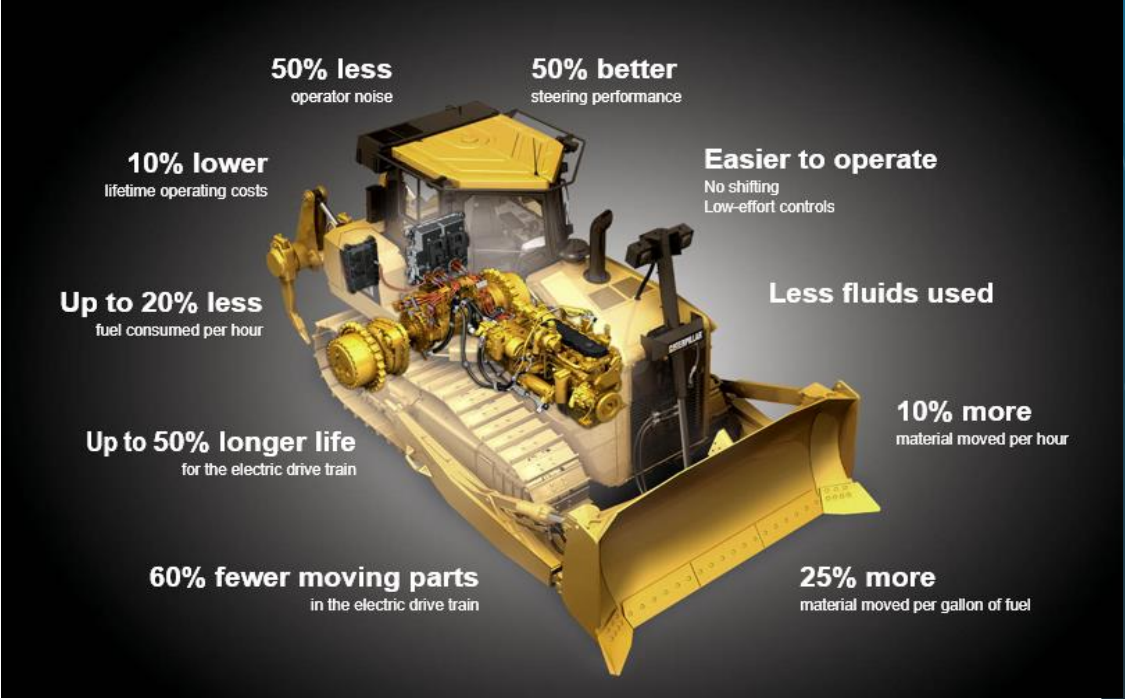
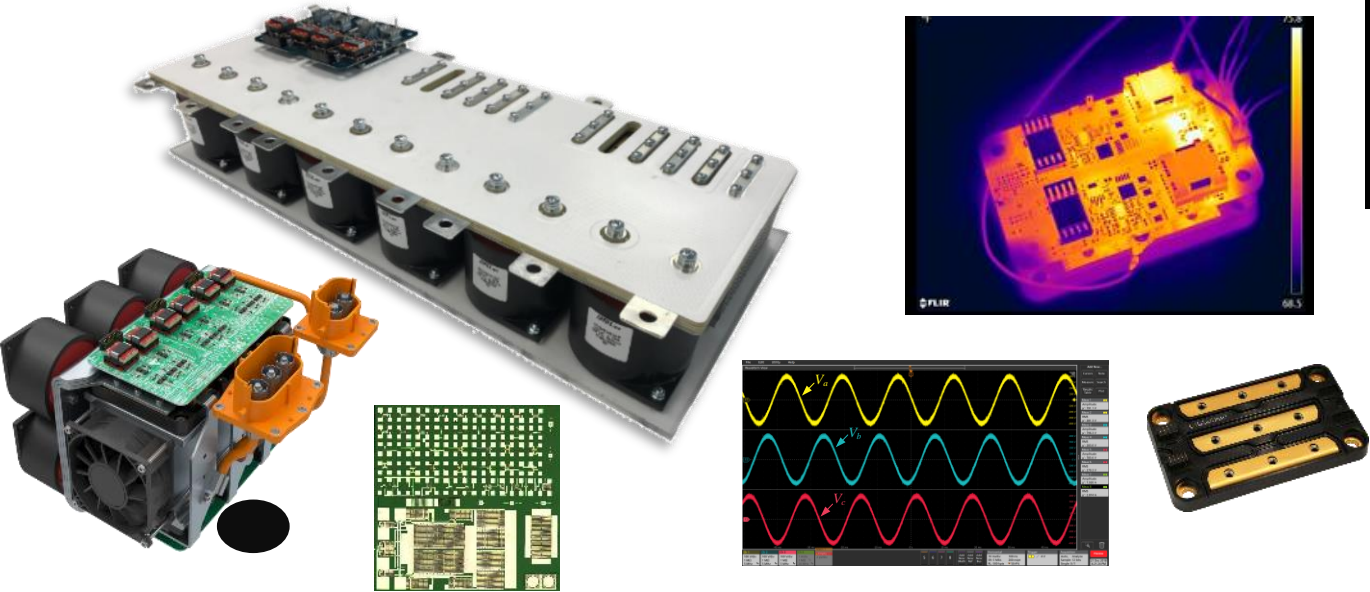
4. Manage reliability to reduce risk and cost



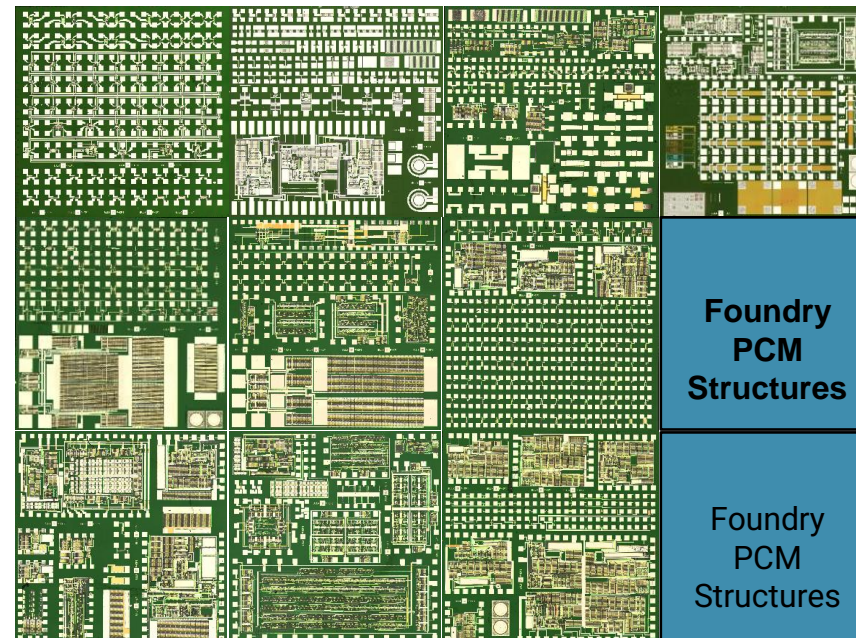
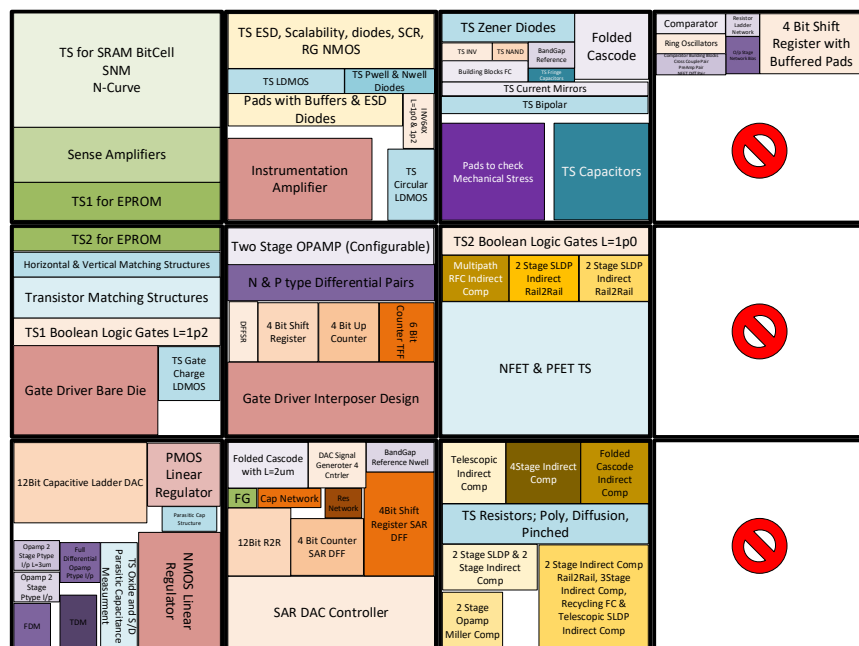
# Reliable, High Power Density Inverters for Heavy Equipment Applications

University of Arkansas: Alan Mantooth

Metric	State of the Art	Proposed
Power Output	2×70 kW	2×250 kW
Peak Efficiency	97%	98.5%
Power Density	5.7 kW/l	25 kW/l
Gravimetric Density	5.6 kW/kg	20 kW/kg
Relative Cost	\$ 20/kW	\$ 10/kW



# SiC CMOS Gate Driver IC



## Gate Driver:

- Gate driver for flip-chip packaging
- Linear regulators

## Test Structures:

- MOSFETs, Diodes, Fringe Capacitors
- Current mirrors
- Differential pairs
- LDMOS

## Digital:

- SRAM
- Counters
- Standard component parts
- Boolean logic
- Registers
- Clock Generators

## Analog:

- Instrumentation amplifier
- ADC, DAC
- Opamp
- Differential
- Comparators
- Sense Amplifier

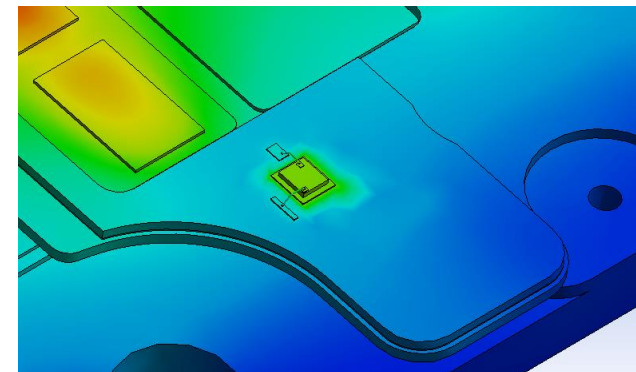
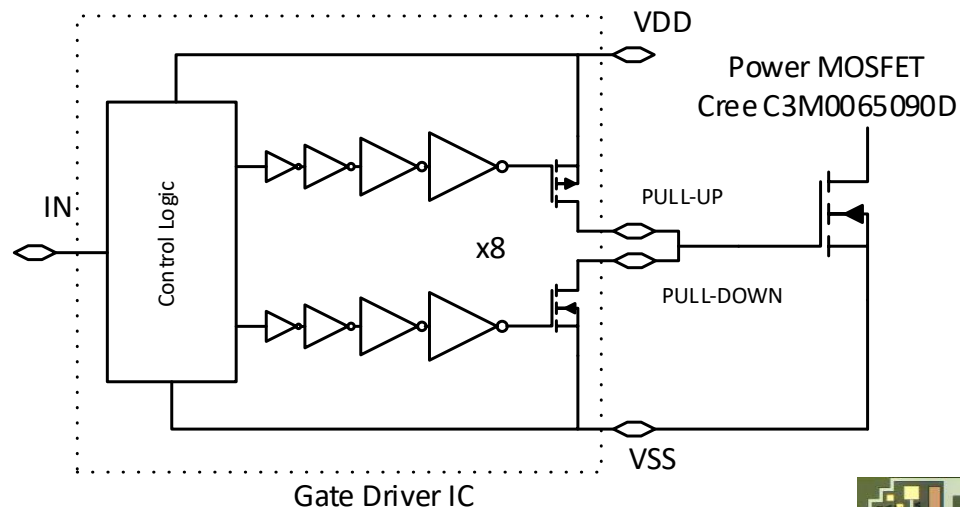




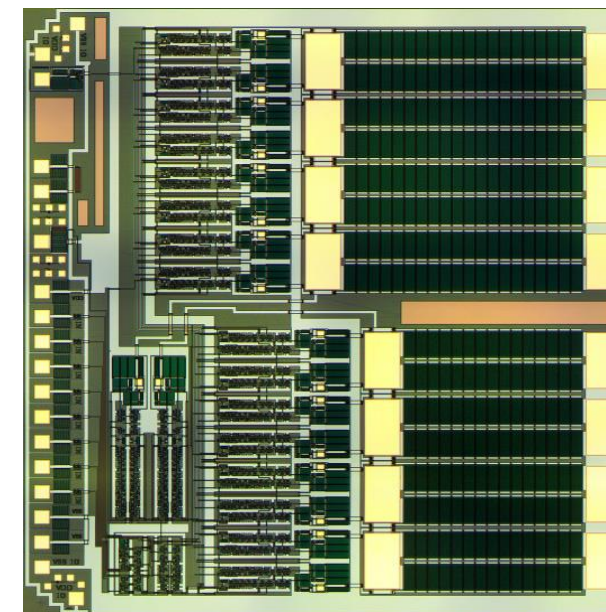
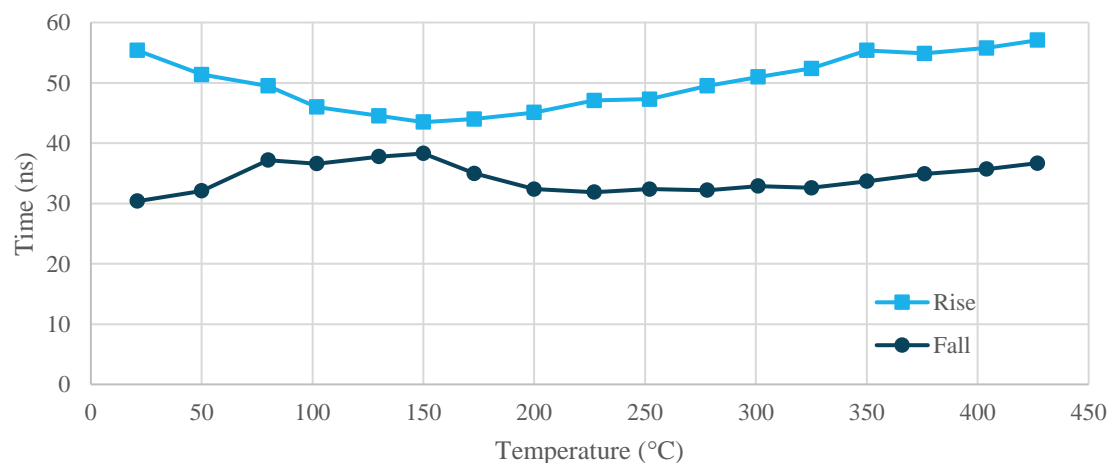
# Gate Driver Circuit

## Features

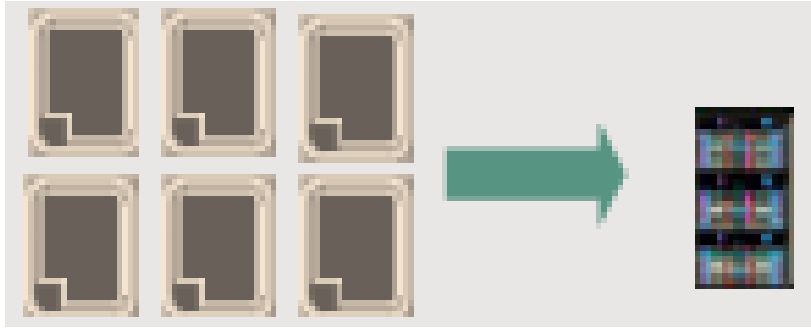
- Variable drive strength
- Built-in test
- Operational to over 400°C



Gate Driver Full Strength Rise and Fall Times

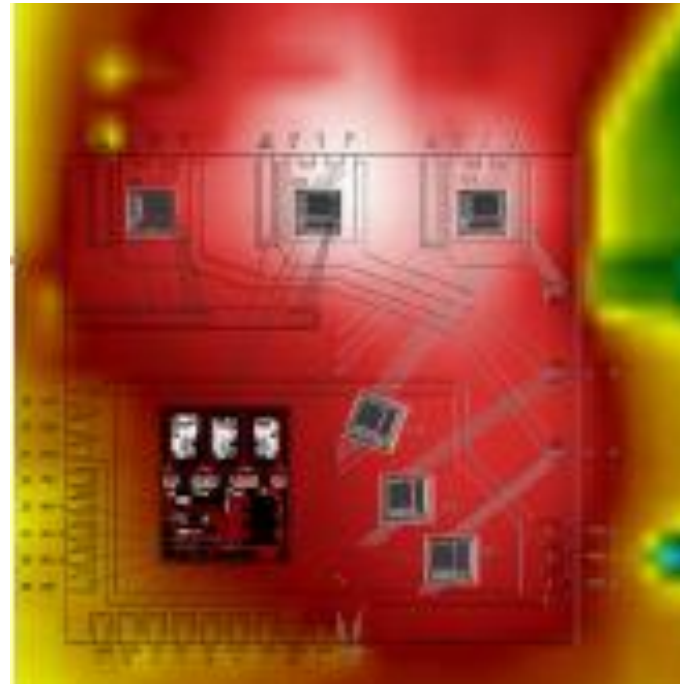


# Integration Of Power Devices – Monolithic Devices

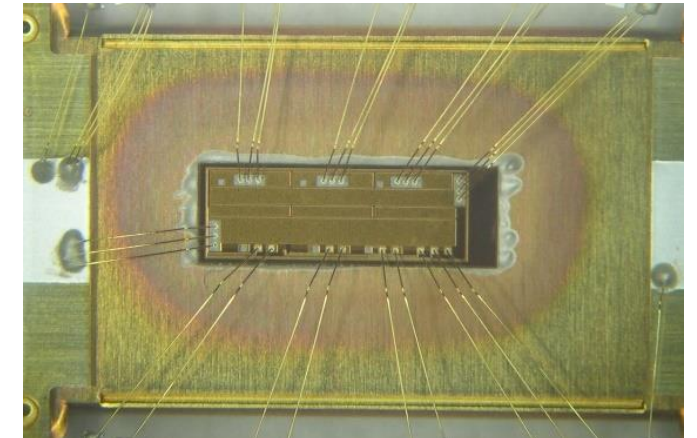


- Monolithic GaN enables better performance at a better cost
- Reduces component cost with smaller GaN switch
- Reduces package cost with simpler package

- Compared to IGBTs, the 3-phase GaN module temperature rise is reduced 50%.
- GaN delivers more than **4x** the power of SOA Si for consumer motor application



650V/0.5Ω 3-phase Monolithic GaN

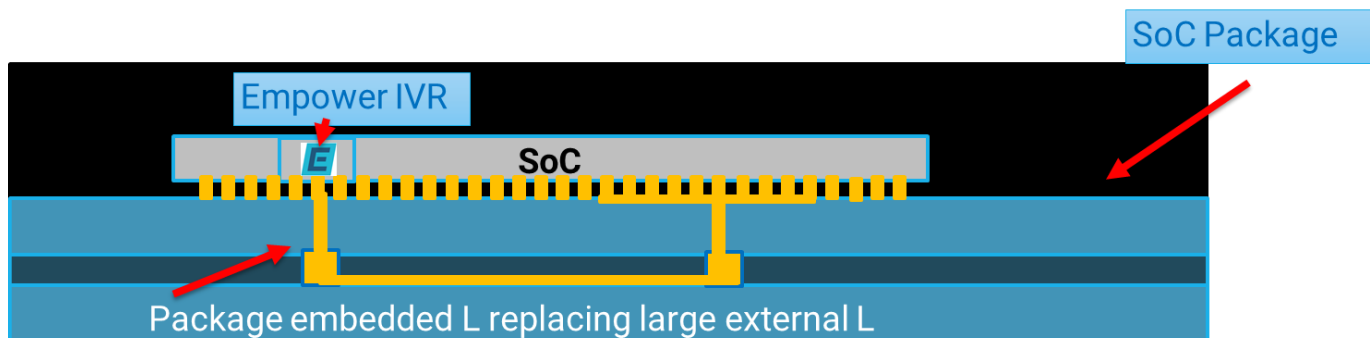
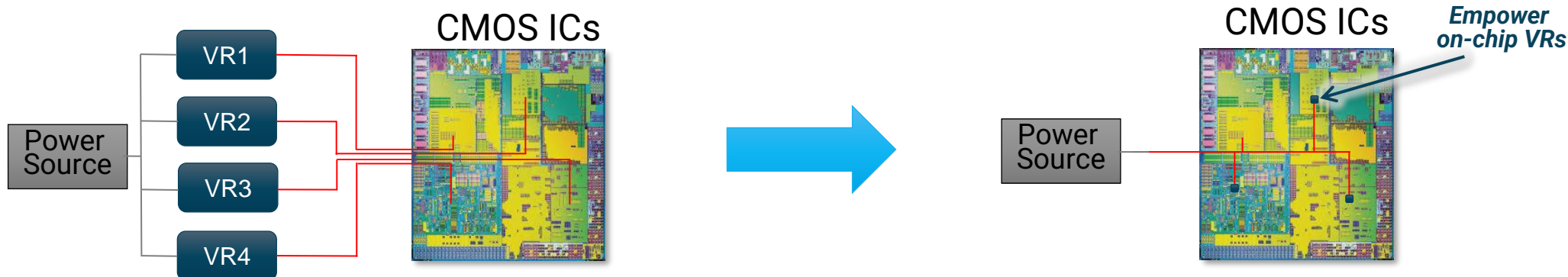


(Test condition: 300Vdc, 0.5Arms, 16khz, 720rpm, 60Hz with 10-pole PM motor, DT=1us, 2 phase modulation.)



# Full Integration Of Power Delivery

- Integrated circuits require multiple voltage supplies for various functions.
- Traditionally, all but the lowest power levels are regulated externally



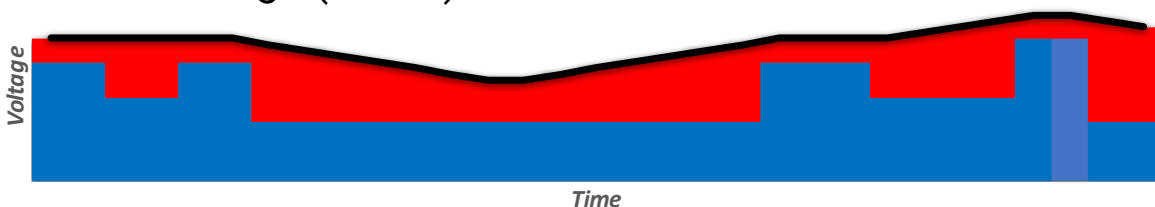
- Resonance architecture ensures switching occurs at low currents
- Architecture and switching speed enables large external inductors to be replaced with metal traces in the package
- Fast regulation eliminates external output caps



# Fast Dynamic Voltage Scaling Enables Power Savings

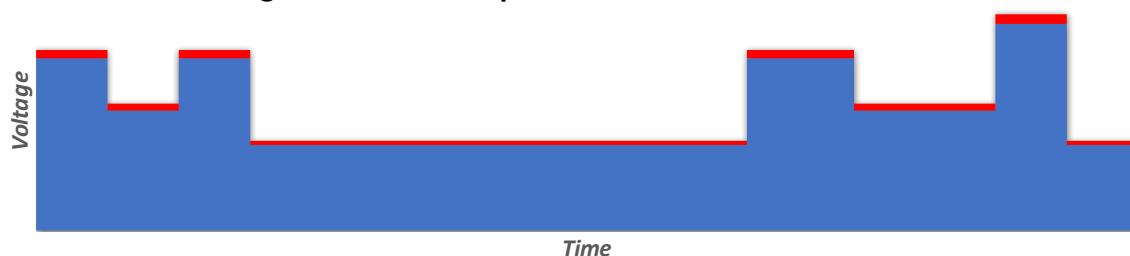
## State of the Art

- Voltage set high to handle current transients for any fixed voltage
- Existing power solutions too slow to react to voltage changes Significant power is wasted with the excess voltage ( $P \sim V^2$ )



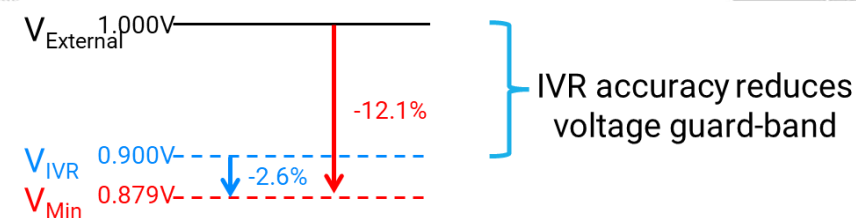
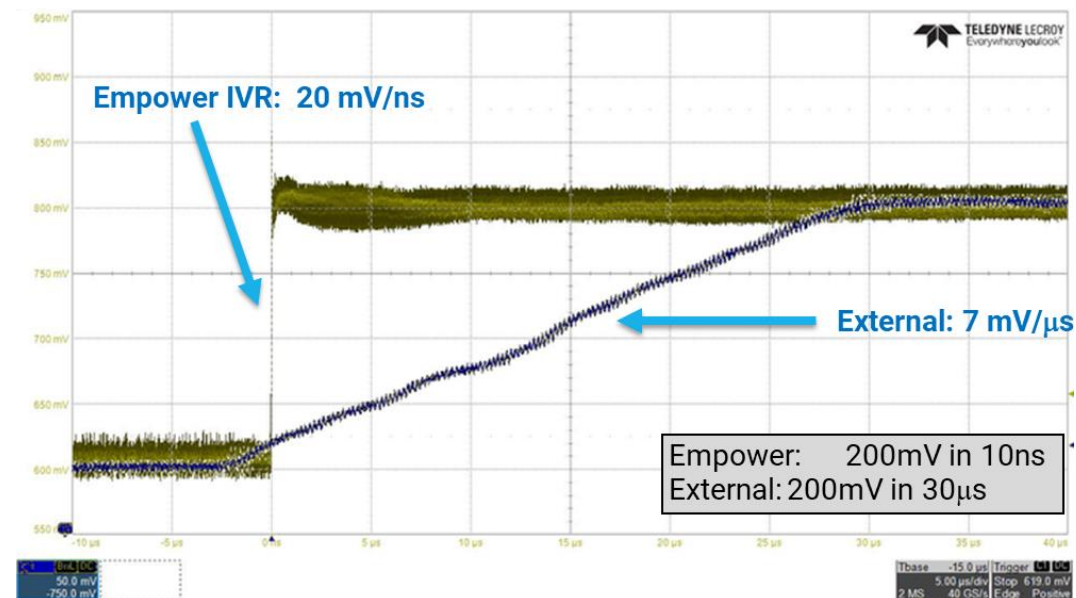
## Empower's Integrated VR

- Tight voltage regulation saves power at any fixed voltage level
- "Instantaneous" voltage delivery eliminates excess voltage & wasted power at the load



■ Voltage Required ■ Power Wasted — Voltage Delivered

Empower steps voltage on demand 3,000x faster

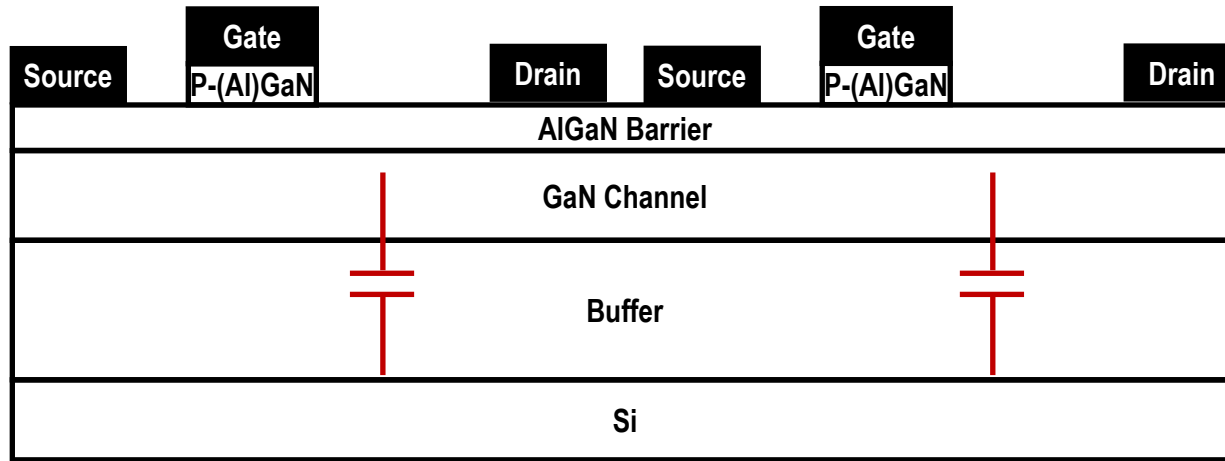


$$\text{Power Savings} = 1 - \frac{(V_{IVR})^2}{(V_{Ext})^2} = 19\%$$

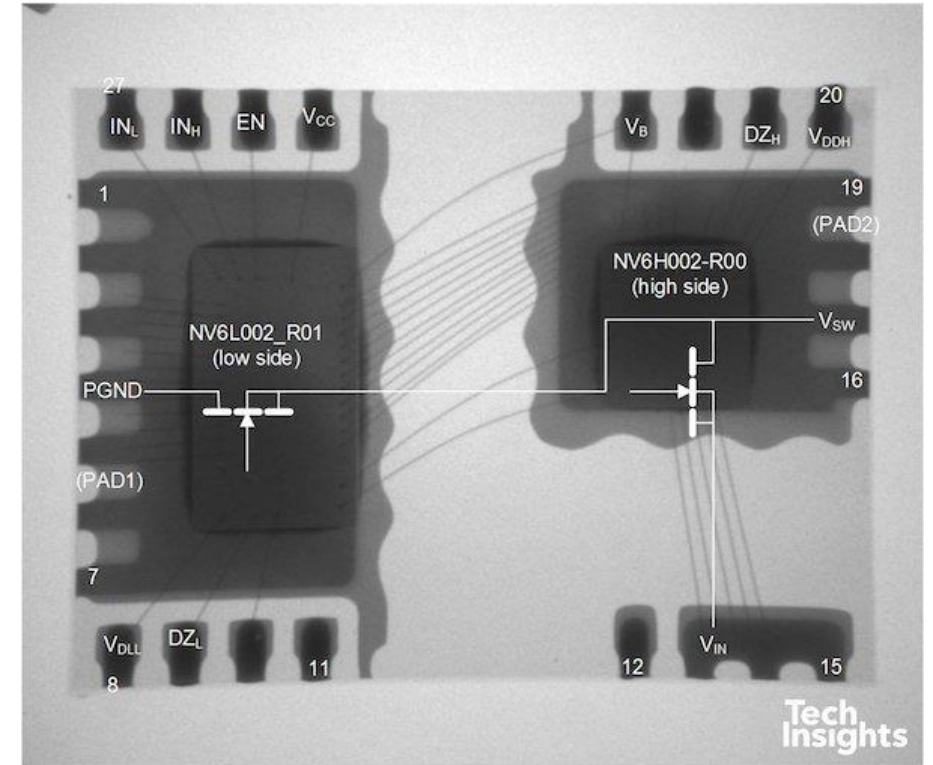




# GaN Power IC Challenge 1: Back Gating Effects



- Si substrate does not provide sufficient high voltage isolation between high- and low-side switches
- Back gating effects of Si substrate adversely affect switching performance
- Commercial half-bridge “IC” separates high- and low-side switches into two dies....**adding additional parasitic inductance.**



<https://www.techinsights.com/blog/revisiting-seminal-apa-optics-gan-hemt-patent>



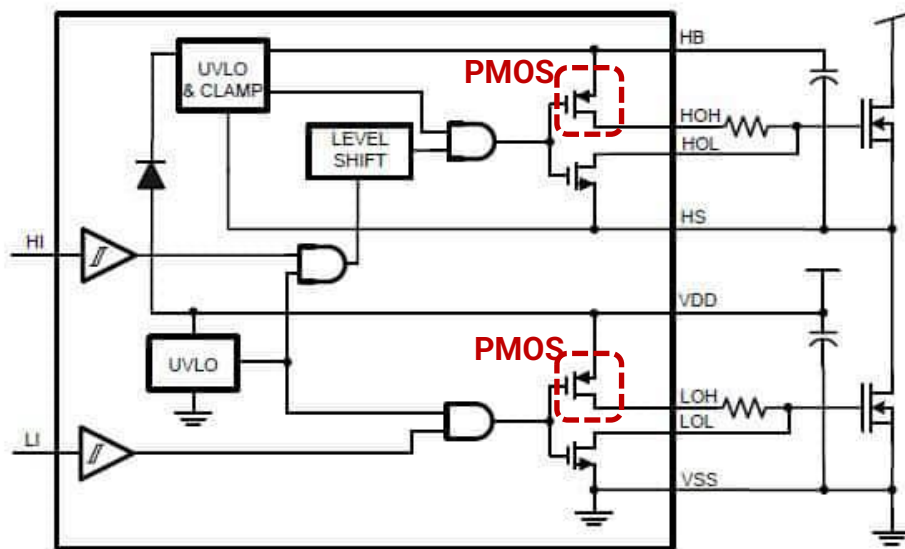
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CHANGING WHAT'S POSSIBLE



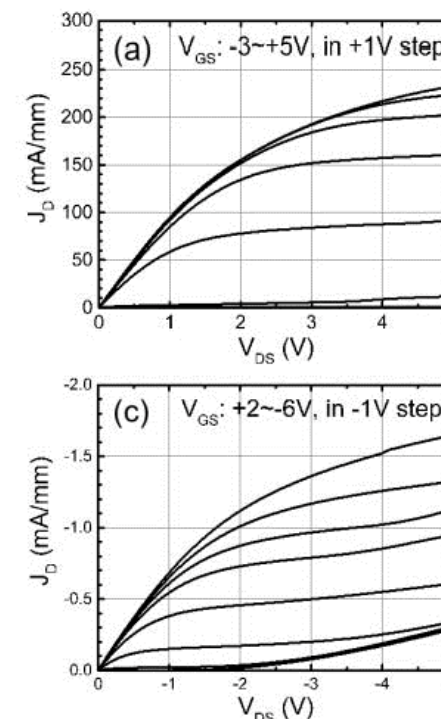
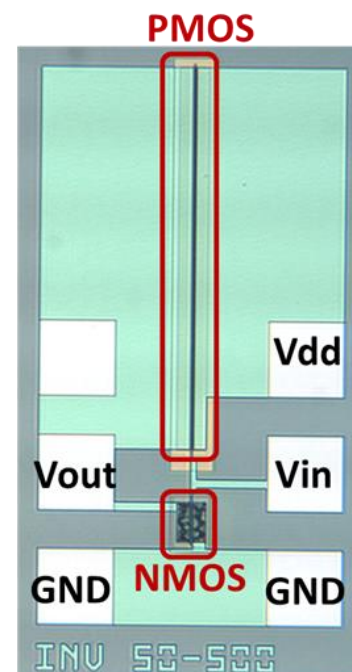


# GaN Power IC Challenge 2: CMOS



<https://www.digikey.com/en/articles/selecting-gate-driver-ics-for-gallium-nitride-fets>

- Gate driver prefers PMOS for pull-up
- GaN PMOS is possible, but still of very low performance
- Mobility of  $\sim 20 \text{ cm}^2/\text{V-sec}$  for holes versus  $\sim 2000 \text{ cm}^2/\text{V-sec}$  for electrons
- Ohmic contact to p-GaN highly resistive



NMOS:  
 $I_d = \sim 200 \text{ mA/mm}$

PMOS:  
 $I_d = \sim 2 \text{ mA/mm}$

Chu, Rongming, et al. "An experimental demonstration of GaN CMOS technology." *IEEE Electron Device Letters* 37.3 (2016): 269-271.

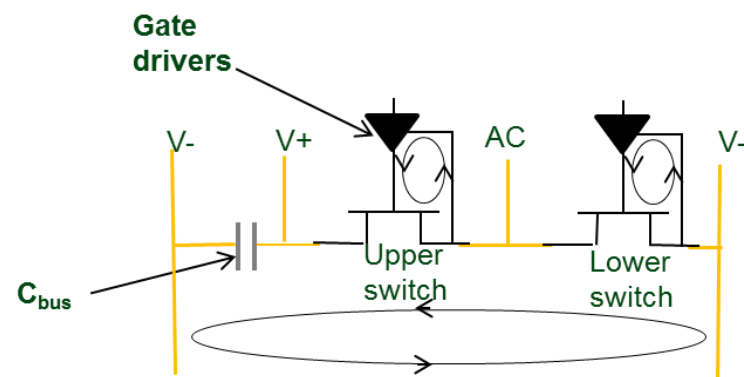


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# GaN Power IC Challenge 3: Passives



- Bus capacitor is also in the power loop
- Monolithic integration of bus capacitor desired
- Challenging to fabricate on-chip capacitors with high blocking voltage and large enough capacitance value
- Direct mount of the bus capacitor on top of the half-bridge chip?
- Switch at a much higher frequency to reduce capacitance value?

Cross-section	Calculated parasitic inductance
	0.90 nH
	0.87 nH
	0.39 nH

Hashimoto, T., et al. "System in package with mounted capacitor for reduced parasitic inductance in voltage regulators." 2008 Twenty-Third Annual IEEE Applied Power Electronics Conference and Exposition. IEEE, 2008.



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# GaN IC Status

## IMEC

### Integrated driver for fast switching

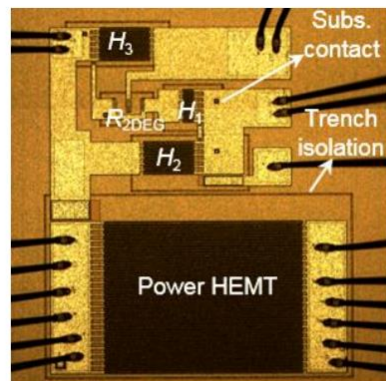
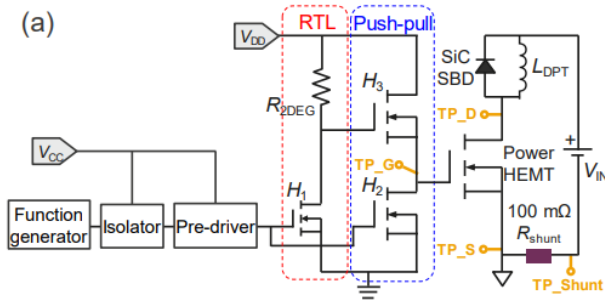
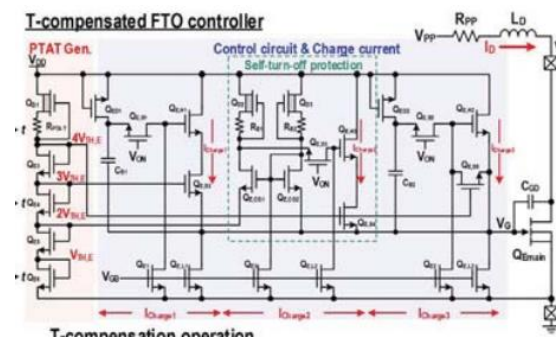
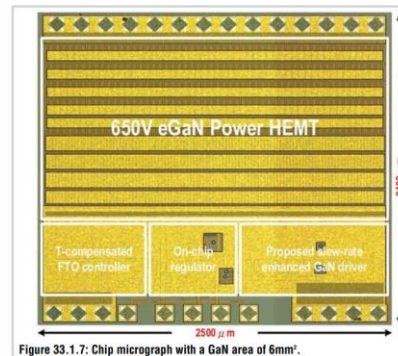


Figure 5.21: Microscopy photograph of the monolithically integrated driver and power HEMT with trench isolation.

Y. Yamashita, S. Stoffels, N. Posthuma, K. Geens, X. Li, J. Furuta, S. Decoutere, and K. Kobayashi, "Monolithic integration of gate driver and p-GaN power HEMT for MHz switching implemented by e-mode GaN-on-SOI process", IEICE Electronics Express, vol. 16, no. 22, pp. 20190516- 20190516, 2019.

## TSMC

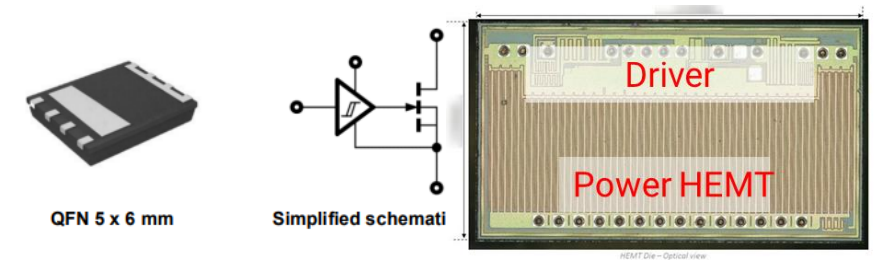
### Fully integrated 12V GaN driver and a 650V eGaN power HEMT switch



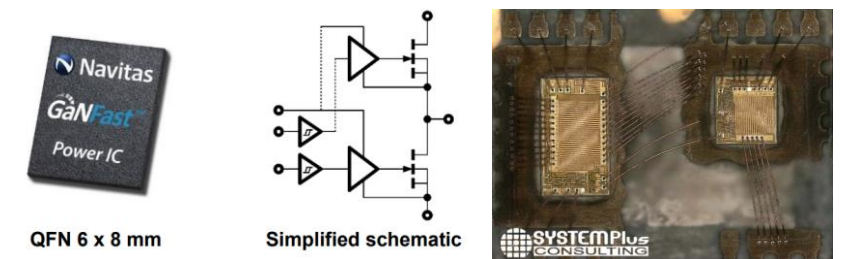
ISSCC 2021 / SESSION 33, Chen et.al., "A Fully Integrated GaN-on-Silicon Gate Driver and GaN Switch with Temperature-compensated Fast Turn-on Technique for Improving Reliability"

## Navitas products

### NV6115: low-side transistor with driver



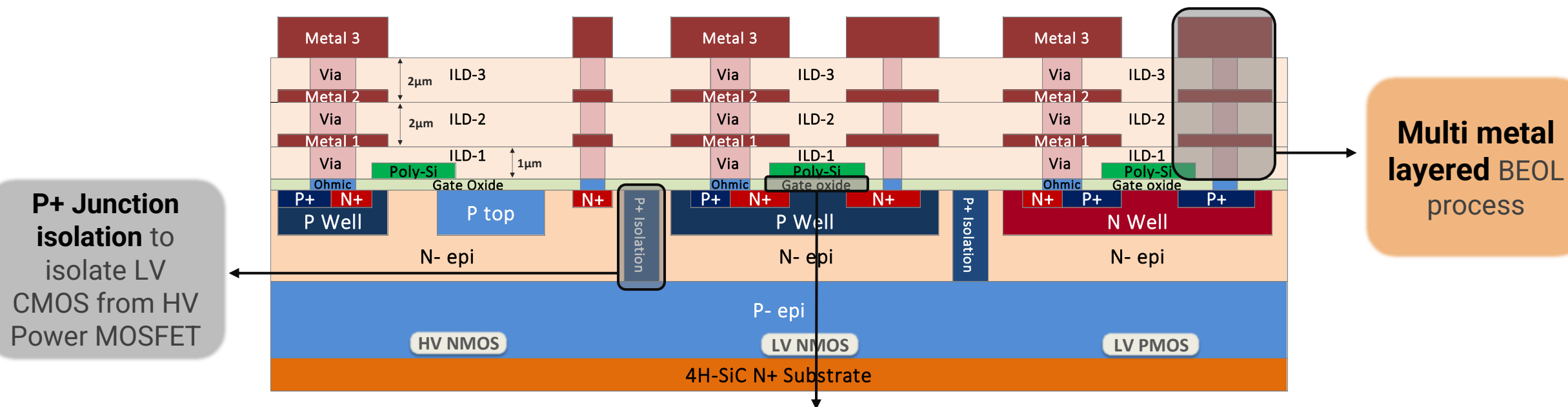
### NV6252: half bridge module with 2 chips integrating the drivers



# SiC Power IC with HV Power MOSFET integrated with LV CMOS

**Nepi/Pepi/N+ substrate** stack for monolithic integration of HV Power MOSFET and LV CMOS circuitry

**Single process flow** to fabricate the HV Power MOSFET, LV NMOS and LV PMOS



**P+ Junction isolation** to isolate LV CMOS from HV Power MOSFET

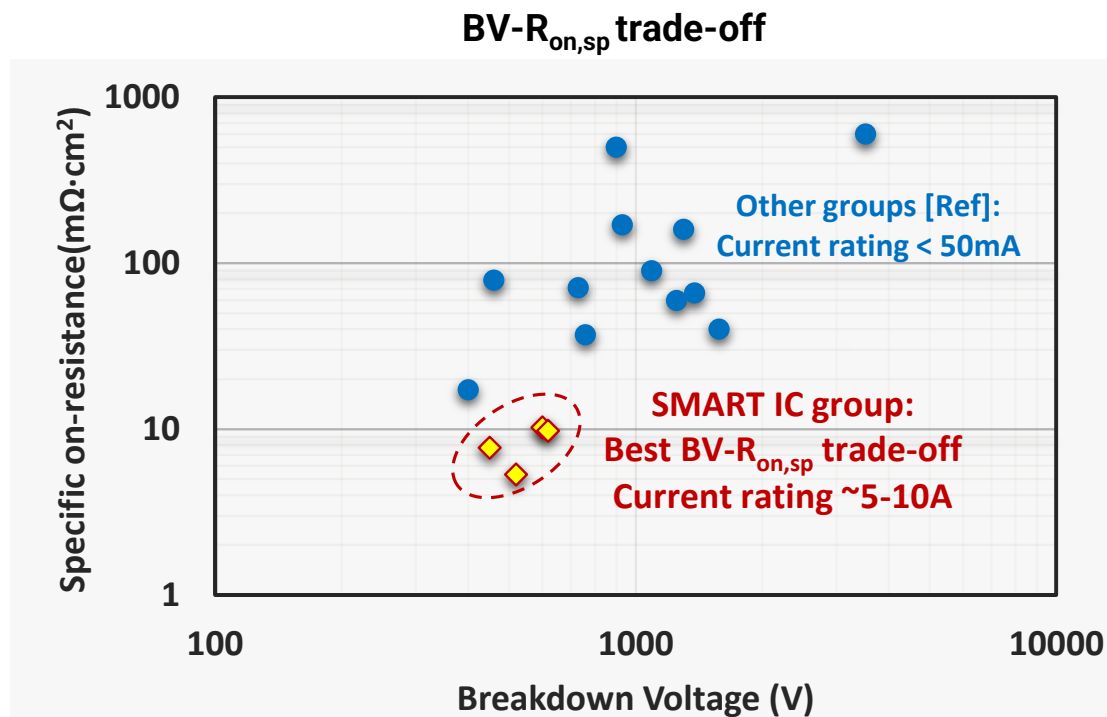
**Multi metal layered BEOL** process

Development of **novel gate oxide recipes** for high channel mobilities



# HV and LV SiC IC Device Characteristics

## HV Power nMOSFET

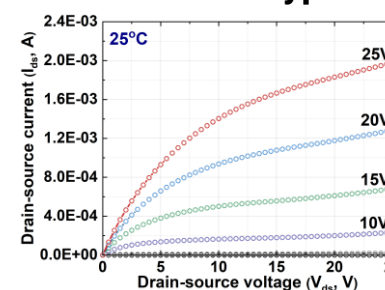


- **Best in class with superior BV-  $R_{on,sp}$  trade off**
  - **Large current rated devices**

## LV CMOS

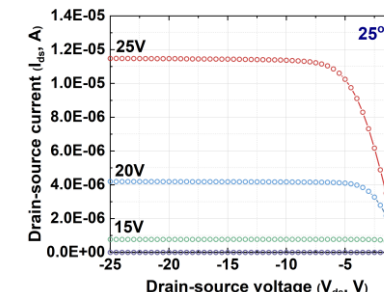
### LV NMOS

#### Typical output characteristics

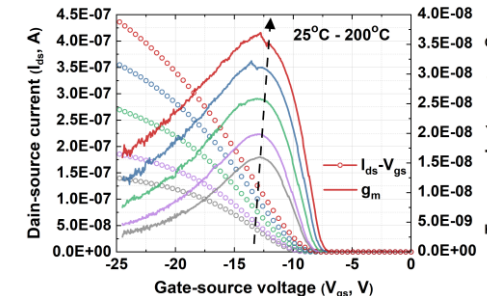
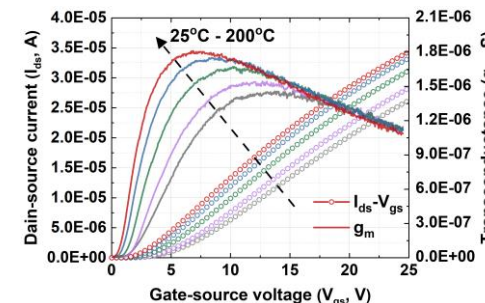


### LV PMOS

#### Typical output characteristics



#### Typical transfer characteristics

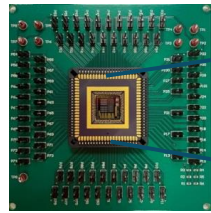


- **Stable LV CMOS operation up to 200°C**

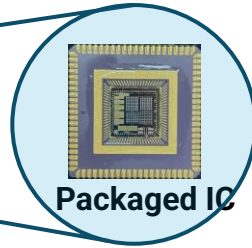




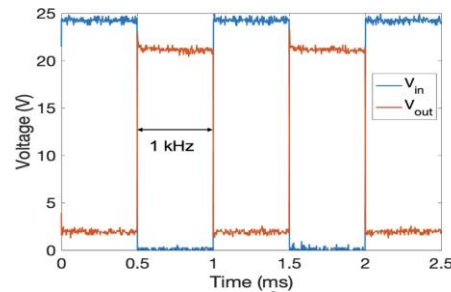
# SiC IC Circuit Characteristics



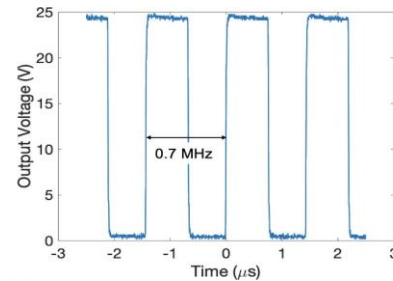
Evaluation PCB



Packaged IC

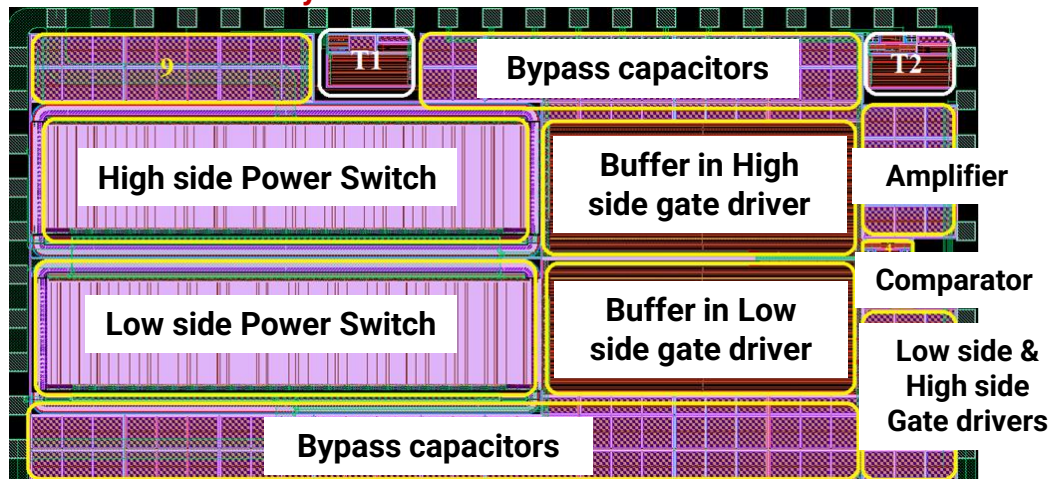


Measurement of the Inverter Gate



Measurement of the Oscillator

Layout view of a SiC buck converter



## Scalable :

- High power rated ( $>1\text{kW}$ ) ICs
- Large number of gates ( $\sim 10,000$ )
- Fabrication of large current (1A), high voltage devices

## Manufacturable

- Proven, mature process technology for SiC vertical power devices
- Establishment of process baseline at state-of-the art, SiC fabrication facility

## Robust

- Leveraging field proven reliability of HV Vertical SiC devices
- Improving gate oxide reliability
- Establishing robust and rugged designs for SiC CMOS

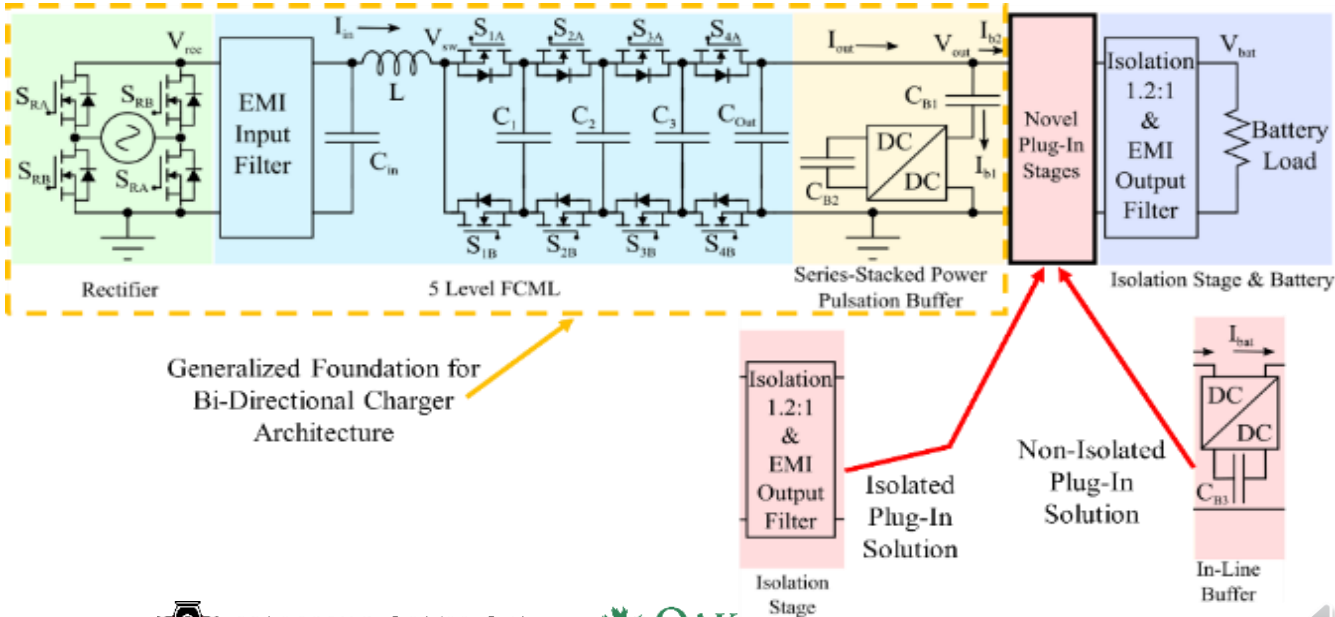
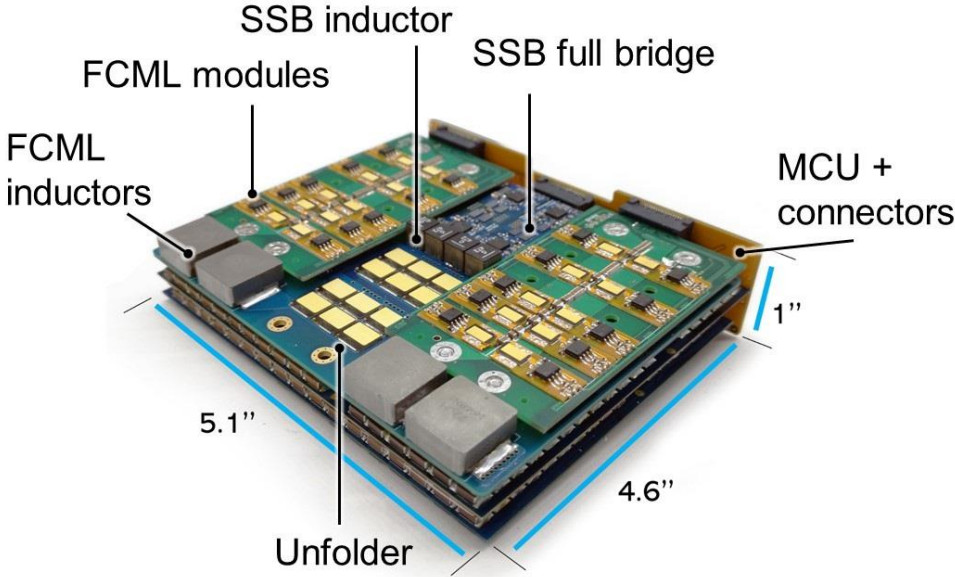
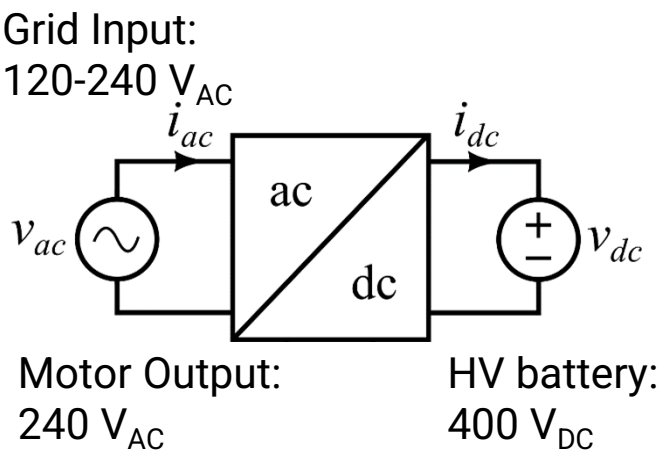
- Demonstration of 4H SiC CMOS inverter and ring oscillator
- Layout of 4H-SiC CMOS based buck converters



# Enabling Ultra-Compact, Lightweight, Efficient, and Reliable 6.6 kW On-Board EV Charger

University of California: R. Pilawa

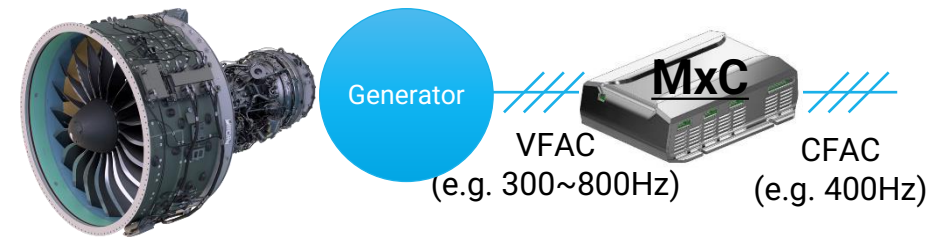
Metric	State of the Art	CIRCUITS Program Goal	Achieved To Date
Power Density	1 kW/L	$\geq 9.15$ kW/L	47.9 kW/L
Specific Power	0.61 kW/kg	$\geq 5$ kW/kg	24.6 kW/kg
Peak Efficiency at rated Power	95.5 %	$\geq 97.5$ %	98.9 %



# Novel Current Source Matrix Converter (MxC)

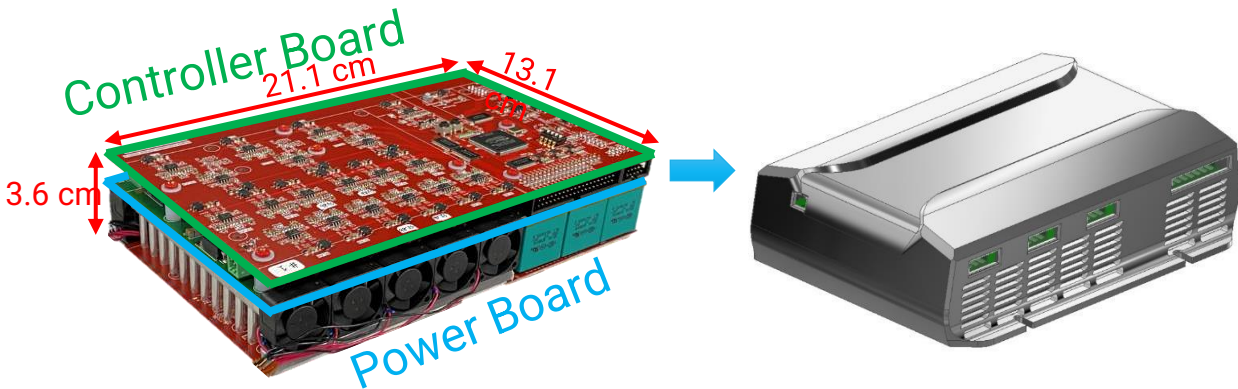
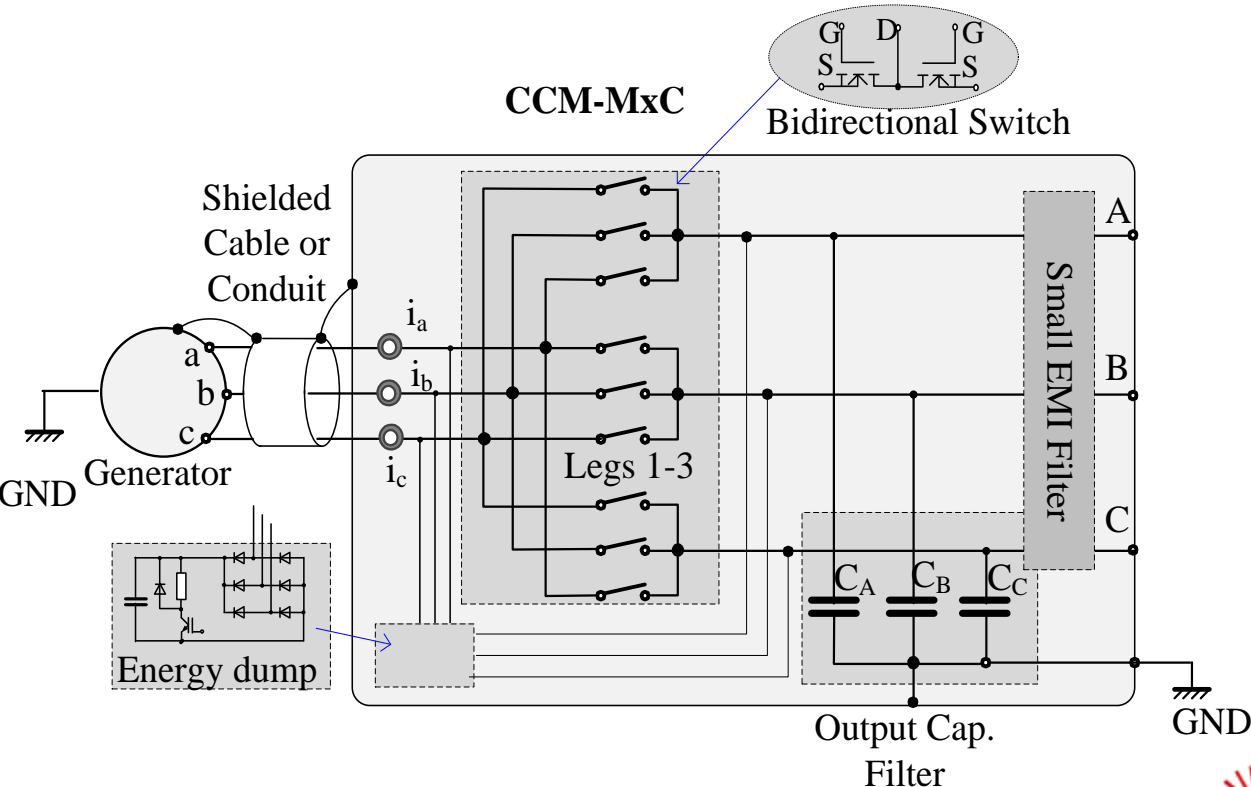
Raytheon Technologies: Vladimir Blasko

## Direct AC-AC conversion from Variable to Constant Frequency

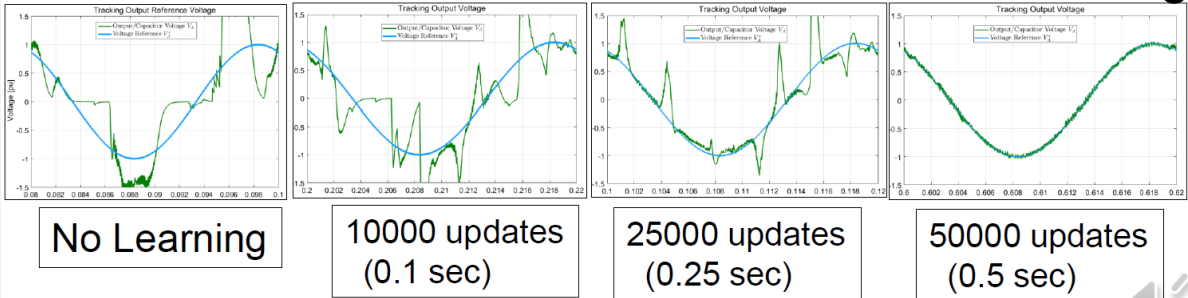


- ▶ Single-stage power conversion
- ▶ Uses 1.2 kV, 115 A SiC MOSFETS
- ▶ Step-up mode with voltage boost

Metric	State of the Art	Proposed
Power Density	1 kW/L	15 kW/L
Specific Power	0.61 kW/kg	≥ 5 kW/kg
Peak Efficiency	95.5%	≥ 99% @ Prated



## Model Predictive Control with Reinforcement Learning



Raytheon  
Technologies



VIRGINIA  
TECH

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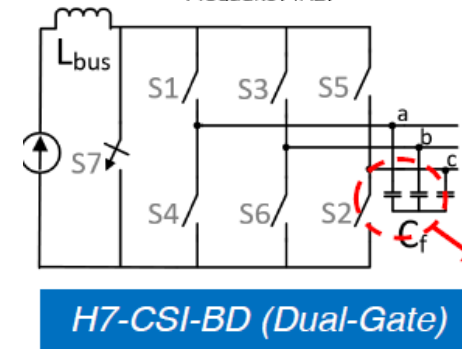
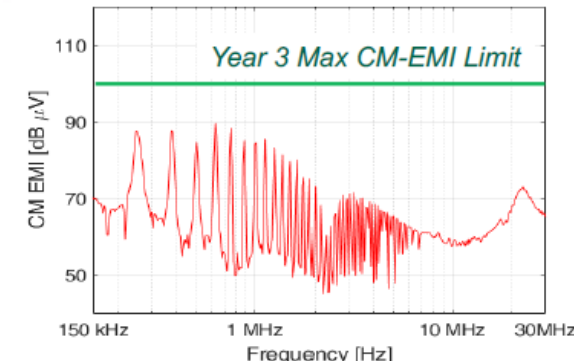
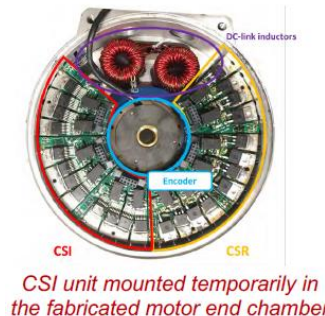


# WBG-Enabled Current Source Inverters for Integrated PM Motor Drives

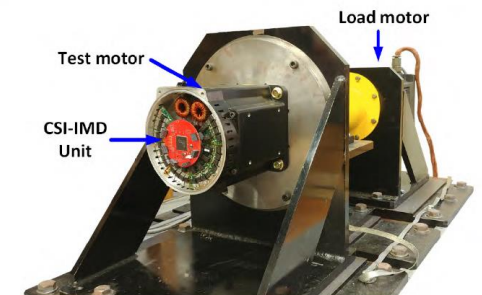
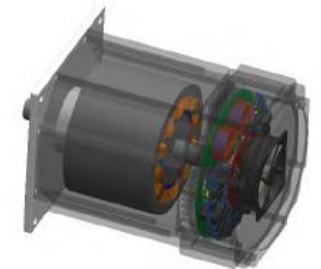
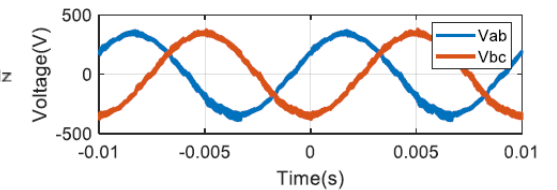
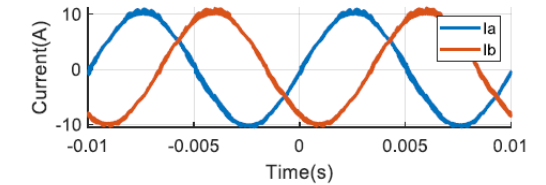
University of Wisconsin at Madison: Thomas Jahns

Metric	State of the Art	Proposed
Switching Frequency	20 kHz	125 kHz
Efficiency @ Full Load	> 97%	> 98%
Efficiency @ Half Load	> 95%	> 96%
Conducted CM-EMI for 150kHz to 30 MHz	< 120 dBuV	< 100 dBuV
THD at Full Load	< 8%	< 1.5%
Power Density	-	> 5 kW/L
Specific Power	-	> 8 kW/kg
Electrical Test Conditions	P <sub>out</sub> = 3 kW, V <sub>ph</sub> = 132 Vrms, I <sub>ph</sub> = 7.6 Arms	

- ▶ Significant reduction in CM-EMI; suitable for aviation application.
- ▶ Very low THD.
- ▶ Using SiC FETs as Bi-directional switch in common source configuration.
- ▶ New CSI topology with improved controls prevents transient short circuit condition



Test Conditions: P<sub>out</sub> = 3 kW, f<sub>sw</sub> = 125 kHz

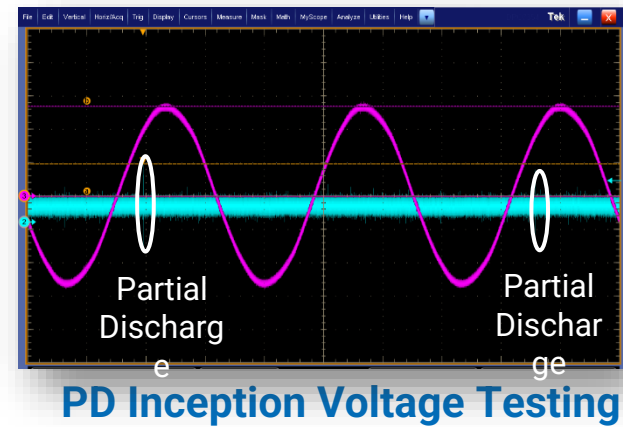
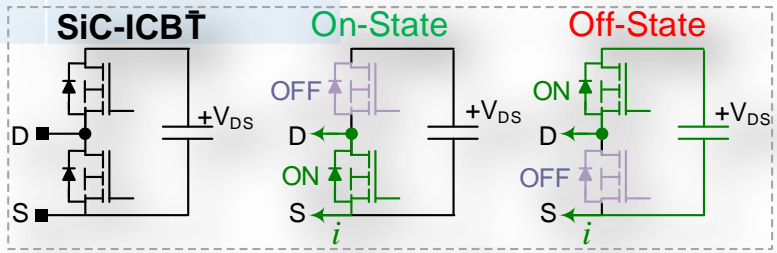
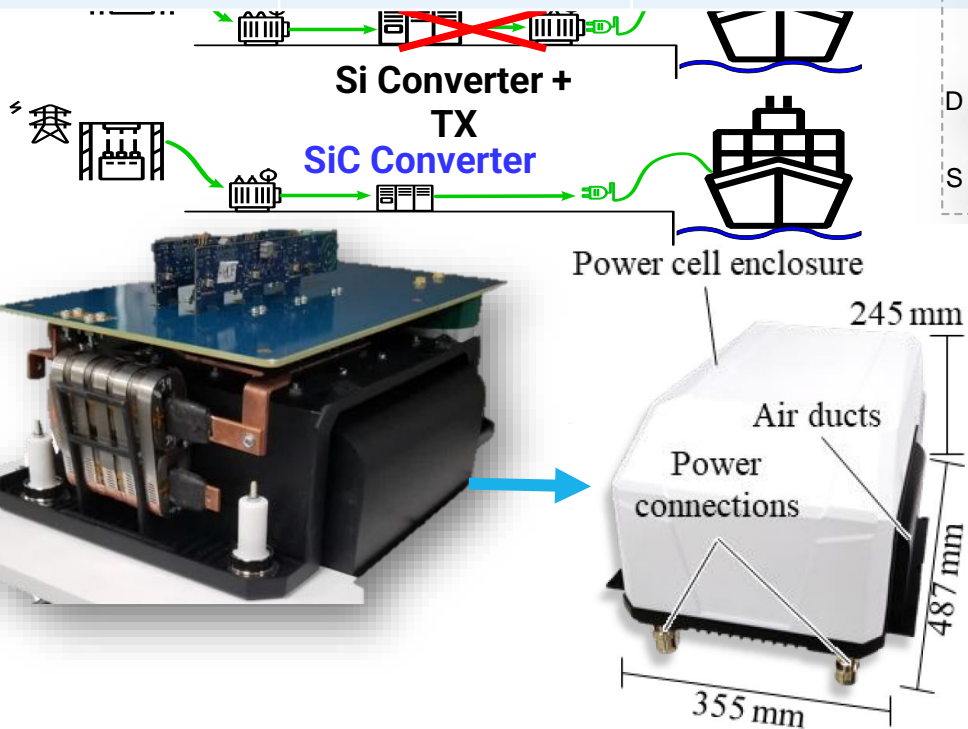
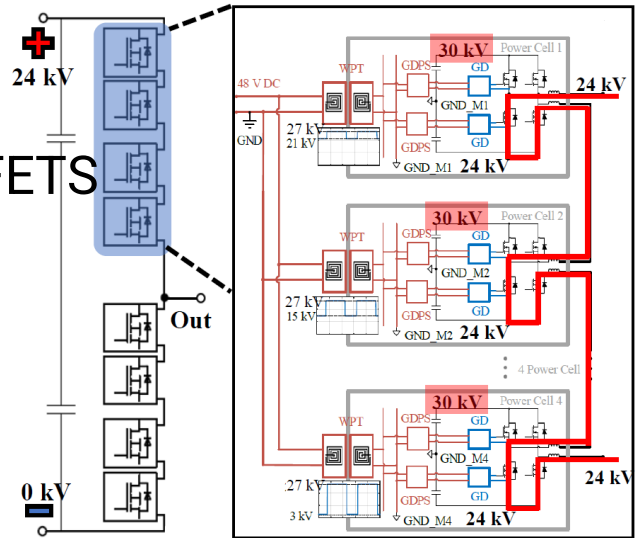


# Modular, Scalable Power Converters for Medium Voltage Applications

Virginia Institute of Technology: Rolando Burgos

Metric	SOA (Ship2Shore)	Est. System (Ship2Shore)	Power Cell
Power density	< 0.28 kW/l	> 3 kW/l	12.9 kW/l
Specific power	< 0.78 kW/kg	> 10 kW/kg	15 kW/kg
Efficiency	97.1 %	99 %	> 99 %
TRL	10	6 (EOP)	

- ▶ 24 kVdc link, >10 kHz switching frequency
- ▶ Uses 10 kV SiC MOSFETS
- ▶ MMC topology with additional states and configurations





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## Dr. Isik C. Kizilyalli

Associate Deputy Director for Technology and Program Director  
Advanced Research Projects Agency – Energy (ARPA-E)

U.S. Department of Energy

[isik.kizilyalli@hq.doe.gov](mailto:isik.kizilyalli@hq.doe.gov)



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